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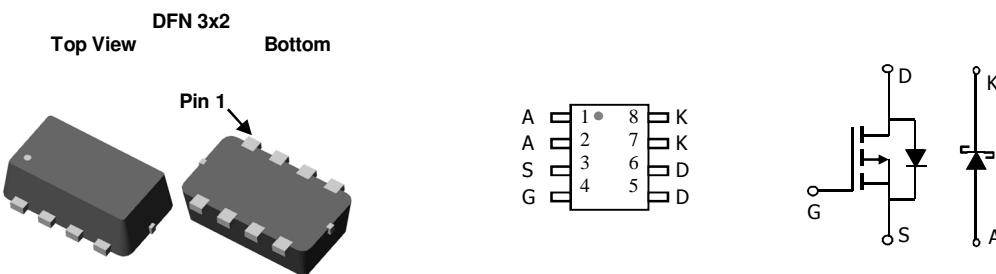
Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

General Description

The AON4703 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. A Schottky diode is provided to facilitate the implementation of a bidirectional blocking switch, or for buck converter applications.

Features

- $V_{DS} (V) = -20V$
- $I_D = -3.4A$ ($V_{GS} = -4.5V$)
- $R_{DS(ON)} < 90m\Omega$ ($V_{GS} = -4.5V$)
- $R_{DS(ON)} < 120m\Omega$ ($V_{GS} = -2.5V$)
- $R_{DS(ON)} < 160m\Omega$ ($V_{GS} = -1.8V$)
- SCHOTTKY**
- $V_{KA} (V) = 20V$, $I_F = 1A$, $V_F < 0.5V$ @ 1A



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | MOSFET | Schottky | Units |
|---|----------------|------------|------------|-------|
| Drain-Source Voltage | V_{DS} | -20 | | V |
| Gate-Source Voltage | V_{GS} | ± 8 | | V |
| Continuous Drain Current ^A | I_D | -3.4 | | A |
| | | -2.7 | | |
| Pulsed Drain Current ^B | I_{DM} | -15 | | |
| Schottky reverse voltage | V_{KA} | | 20 | V |
| Continuous Forward Current ^A | I_F | | 1.9 | A |
| | | | 1.2 | |
| Pulsed Forward Current ^B | I_{FM} | | 7 | |
| Power Dissipation | P_D | 1.7 | 0.96 | W |
| | | 1.1 | 0.62 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | -55 to 150 | °C |

| Parameter: Thermal Characteristics MOSFET | Symbol | Typ | Max | Units |
|---|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 51 | 75 | °C/W |
| Maximum Junction-to-Ambient ^A | | 88 | 110 | |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 28 | 35 | |
| Thermal Characteristics Schottky | | | | |
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 66 | 80 | °C/W |
| Maximum Junction-to-Ambient ^A | | 95 | 130 | |
| Maximum Junction-to-Lead ^C | $R_{\theta JL}$ | 40 | 50 | |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|--|------|-------|-----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=-250\mu\text{A}, V_{GS}=0\text{V}$ | -20 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | | -1 -5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$ | | | ± 100 | nA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=-250\mu\text{A}$ | -0.4 | -0.65 | -1 | V |
| $I_{\text{D(ON)}}$ | On state drain current | $V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$ | -15 | | | A |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance | $V_{GS}=-4.5\text{V}, I_D=-3.4\text{A}$ $T_J=125^\circ\text{C}$ | | 51 | 90 | $\text{m}\Omega$ |
| | | $V_{GS}=-2.5\text{V}, I_D=-2.5\text{A}$ | | 64 | 135 | $\text{m}\Omega$ |
| | | $V_{GS}=-1.8\text{V}, I_D=-1.5\text{A}$ | | 65 | 120 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=-5\text{V}, I_D=-3.4\text{A}$ | | 83 | 160 | $\text{m}\Omega$ |
| V_{SD} | Diode Forward Voltage | $I_S=-1\text{A}, V_{GS}=0\text{V}$ | | -0.7 | -1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | -2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$ | | 560 | 745 | pF |
| C_{oss} | Output Capacitance | | | 80 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 70 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$ | | 15 | 23 | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q_g | Total Gate Charge | $V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-3.4\text{A}$ | | 8.5 | 11 | nC |
| Q_{gs} | Gate Source Charge | | | 1.2 | | nC |
| Q_{gd} | Gate Drain Charge | | | 2.1 | | nC |
| $t_{\text{D(on)}}$ | Turn-On DelayTime | $V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=2.9\Omega, R_{\text{GEN}}=3\Omega$ | | 7.2 | | ns |
| t_r | Turn-On Rise Time | | | 36 | | ns |
| $t_{\text{D(off)}}$ | Turn-Off DelayTime | | | 53 | | ns |
| t_f | Turn-Off Fall Time | | | 56 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=-3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 37 | 49 | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=-3.4\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 27 | | nC |
| SCHOTTKY PARAMETERS | | | | | | |
| V_F | Forward Voltage Drop | $I_F=1\text{A}$ | | 0.4 | 0.5 | V |
| I_{rm} | Maximum reverse leakage current | $V_R=16\text{V}$ | | | 0.2 | mA |
| | | $V_R=16\text{V}, T_J=125^\circ\text{C}$ | | | 20 | mA |
| C_T | Junction Capacitance | $V_R=10\text{V}$ | | 44 | | pF |
| t_{rr} | Schottky Reverse Recovery Time | $I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 11 | 14 | ns |
| Q_{rr} | Schottky Reverse Recovery Charge | $I_F=1\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 2.5 | | nC |

A: The value of R_{gJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{ C}$. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The R_{gJA} is the sum of the thermal impedance from junction to lead R_{gJL} and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using $t \leq 300\mu\text{s}$ pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The SOA curve provides a single pulse rating.

F. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

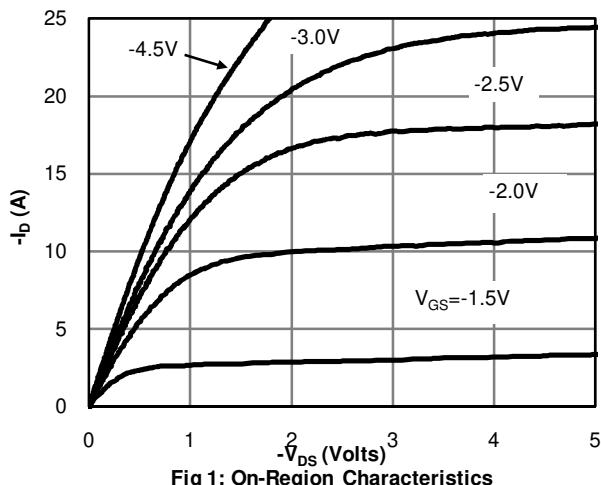


Fig 1: On-Region Characteristics

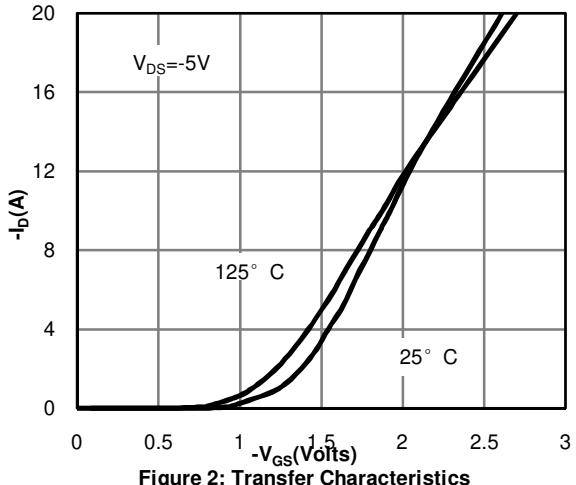


Figure 2: Transfer Characteristics

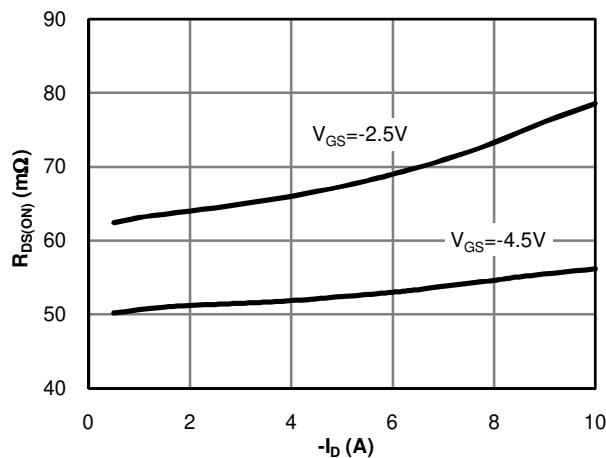


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

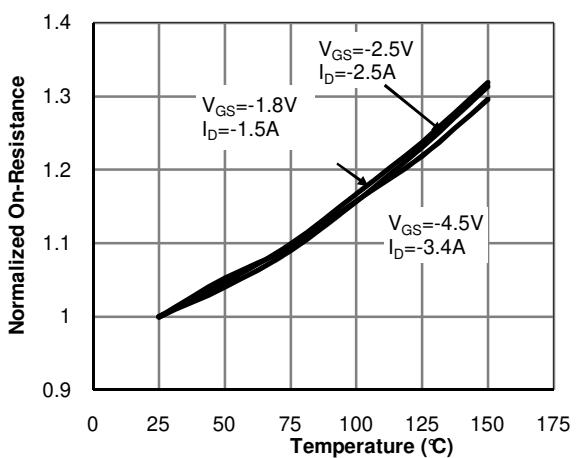


Figure 4: On-Resistance vs. Junction Temperature

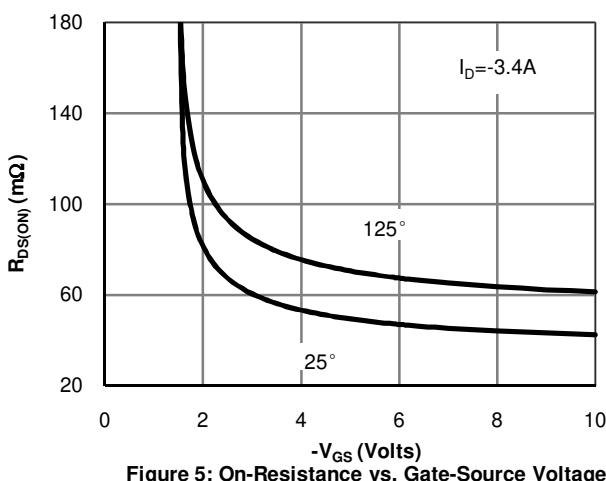


Figure 5: On-Resistance vs. Gate-Source Voltage

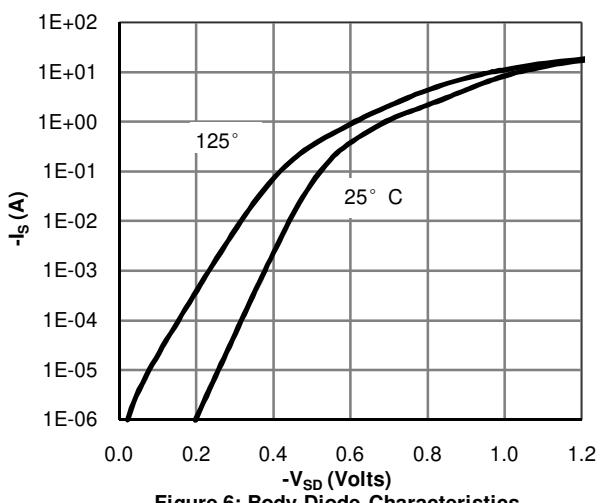
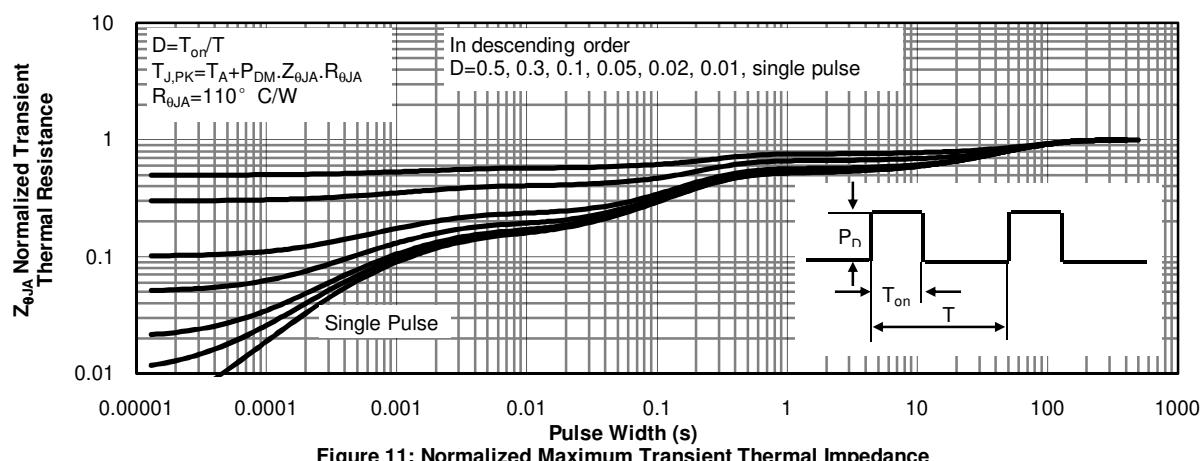
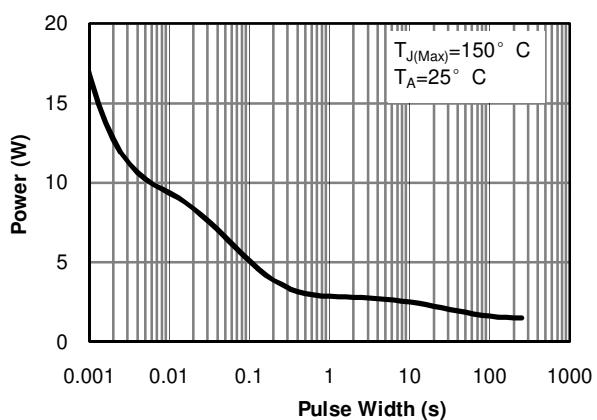
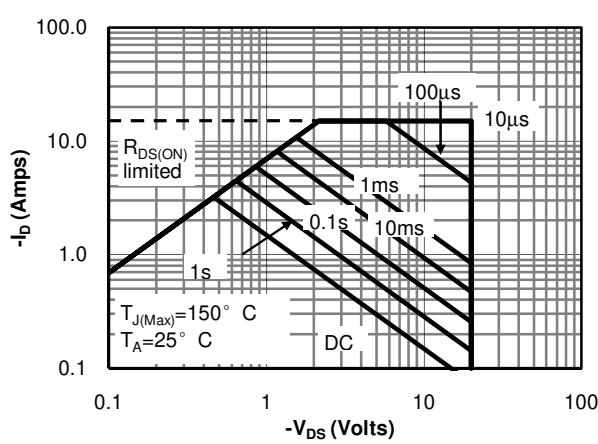
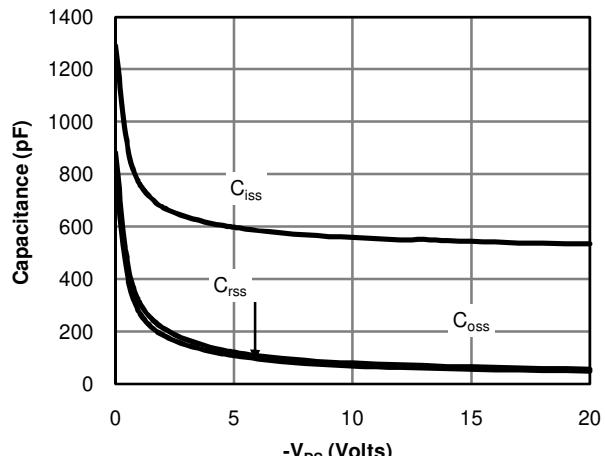
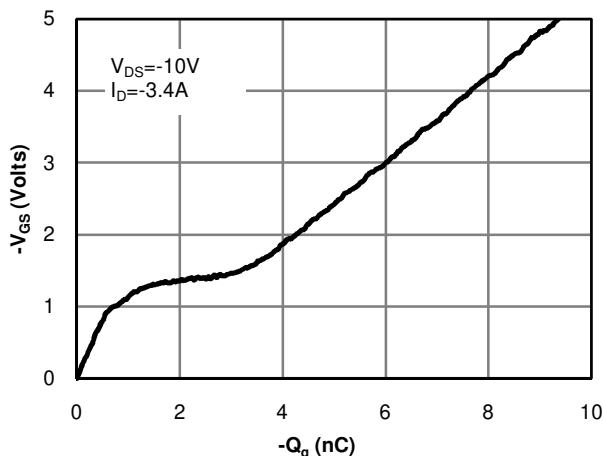
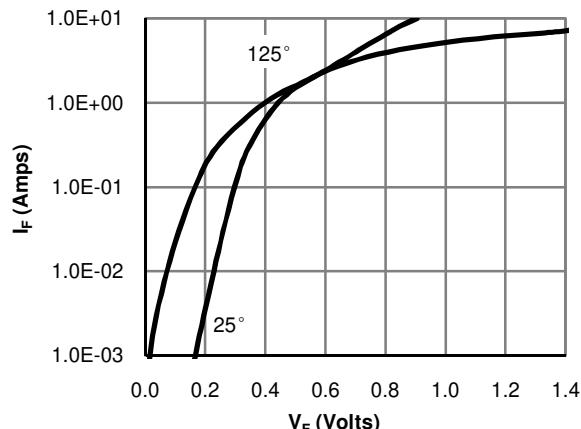
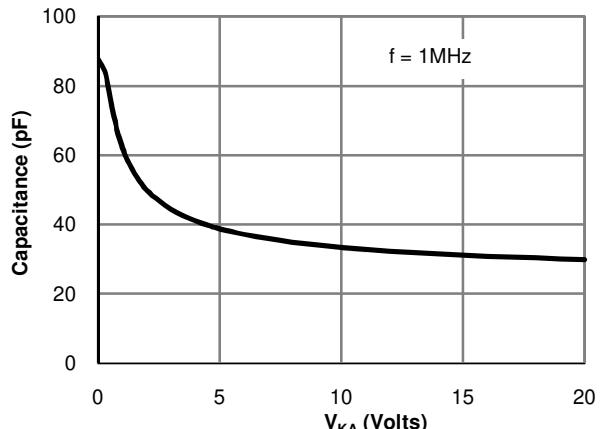
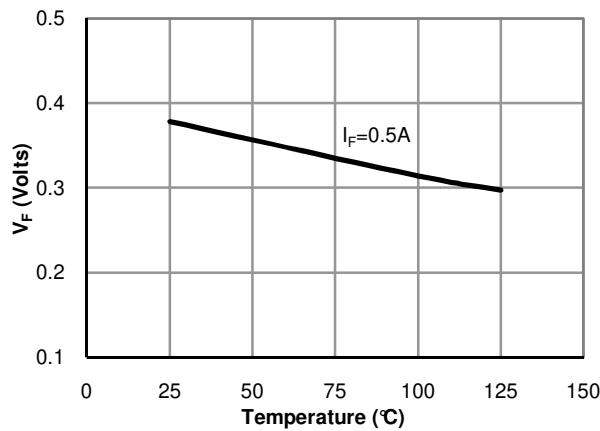
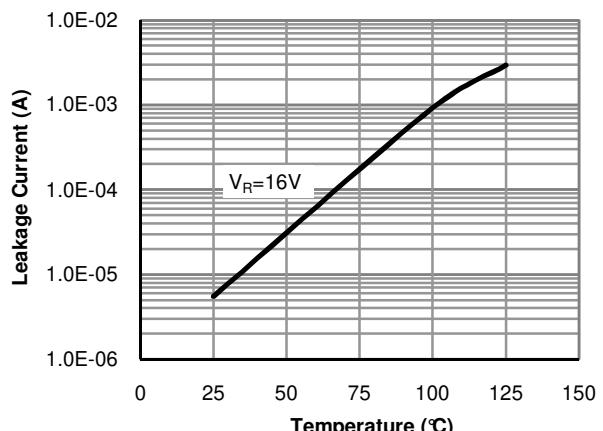
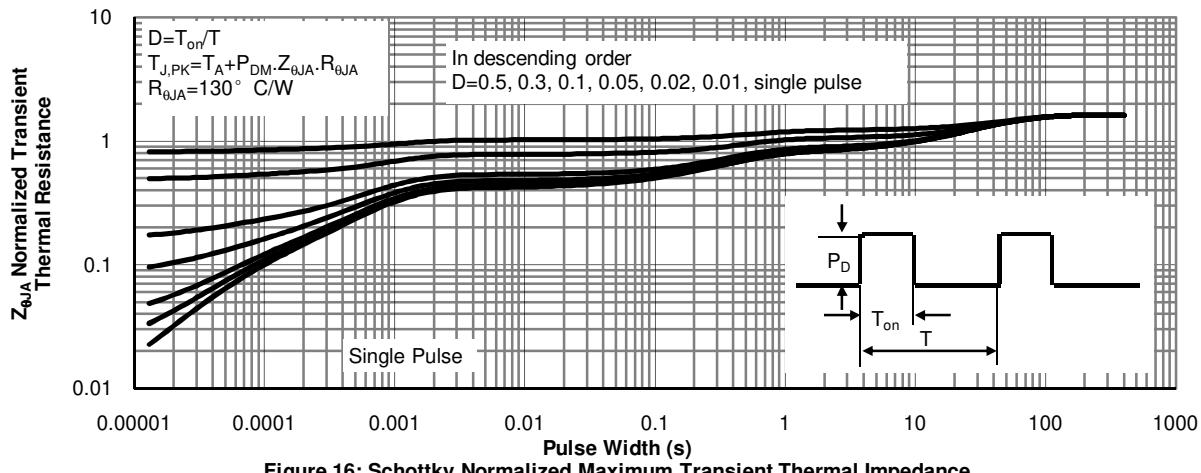
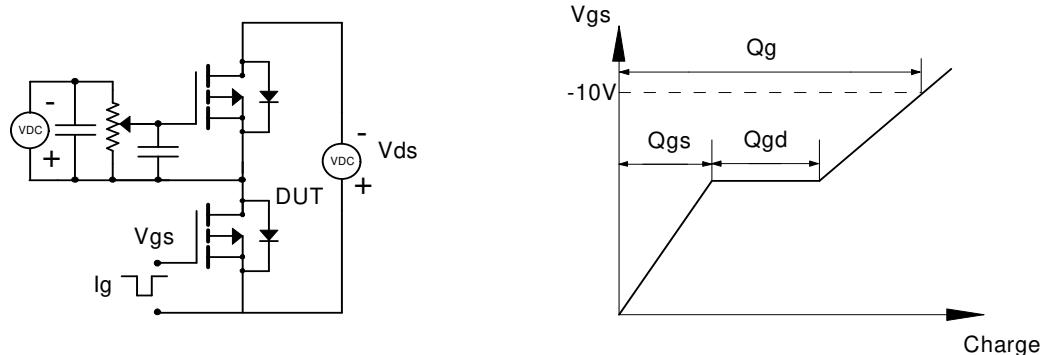
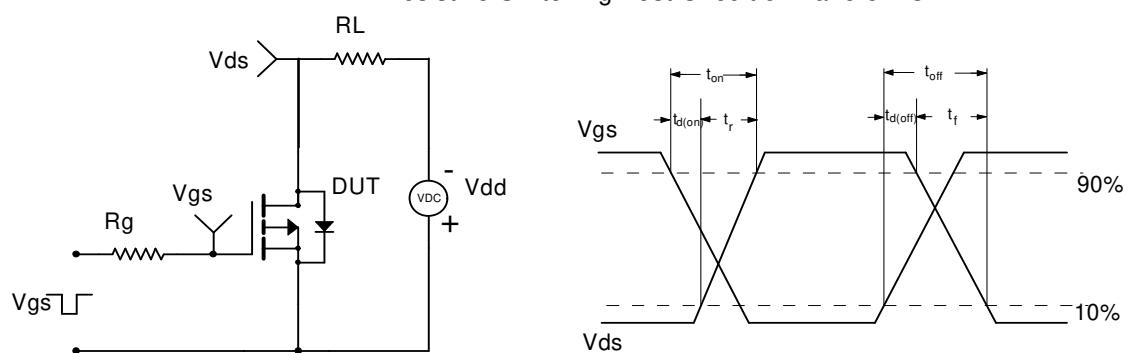


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: SCHOTTKY

Figure 12: Schottky Forward Characteristics

Figure 13: Schottky Capacitance Characteristics

Figure 14: Schottky Forward Drop vs. Junction Temperature

Figure 15: Schottky Leakage current vs. Junction Temperature

Figure 16: Schottky Normalized Maximum Transient Thermal Impedance

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
